

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-1299SERIAL NO.  
09/428,125LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Micron Technology, Inc.FILING DATE  
October 26, 1999GROUP  
2825

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
KR	AA	5,837,591	11/17/98	Shimada et al.			
AB	AB	5,899,740	5/4/99	Kwon			
AC	AC	5,916,634	6/29/99	Fleming et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						



## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

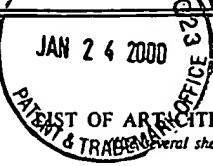
	AR		
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EXAMINER

DATE CONSIDERED

10/9/01

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1299		SERIAL NO. 09/428,125	
LIST OF ARTS CITED BY APPLICANT <small>(Indicate in which column the art is cited, and in which column the art is considered.)</small>						APPLICANT Micron Technology, Inc.			
FILING DATE October 26, 1999						GROUP 2825			

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<div style="font-size: 2em;">KR</div> <div style="font-size: 3em; margin-top: 10px;">↓</div>	AA	4,333,808	6/8/82	Bhattacharya et al.			
	AB	5,585,300	12/17/96	Summerfelt			
	AC	5,641,702	6/24/97	Imai et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
<div style="font-size: 2em;">KR</div>	AL	JP 405,343,641 (Shimada)	12/1993	Japan	257	310	
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)		
<div style="font-size: 2em;">KR</div>	AR	H. Shnriki and M. Nakata, IEEE Transaction On Electron Devices vol 38 No 3 March 1991
	AS	
	AT	

EXAMINER <div style="font-size: 1.5em; font-family: cursive;">K. J. Rose</div>	DATE CONSIDERED <div style="font-size: 1.5em; font-family: cursive;">10/9/01</div>
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